

# IRFIB7N50APbF

HEXFET® Power MOSFET

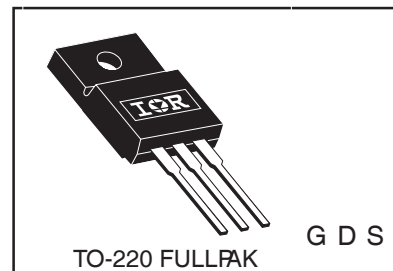
## Applications

- Switch Mode Power Supply ( SMPS )
- Uninterruptable Power Supply
- High speed power switching
- High Voltage Isolation = 2.5KVRMS⑦
- Lead-Free

V <sub>DSS</sub>	R <sub>ds(on)</sub> max	I <sub>D</sub>
500V	0.52Ω	6.6A

## Benefits

- Low Gate Charge Q<sub>g</sub> results in Simple Drive Requirement
- Improved Gate, Avalanche and dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective Coss specified ( See AN 1001)



## Absolute Maximum Ratings

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	6.6	A
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	4.2	
I <sub>DM</sub>	Pulsed Drain Current ①②	44	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	60	W
	Linear Derating Factor	0.48	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ③④	6.9	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

## Applicable Off Line SMPS Topologies:

- Two Transistor Forward
- Half & Full Bridge Convertors
- Power Factor Correction Boost

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## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	500	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔV <sub>(BR)DSS/ΔT<sub>J</sub></sub>	Breakdown Voltage Temp. Coefficient	—	0.61	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA⑥
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.52	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 4.0A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	—	4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	25	μA	V <sub>DS</sub> = 500V, V <sub>GS</sub> = 0V
		—	—	250		V <sub>DS</sub> = 400V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> = 30V
	Gate-to-Source Reverse Leakage	—	—	-100		V <sub>GS</sub> = -30V

## Dynamic @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
g <sub>fs</sub>	Forward Transconductance	6.1	—	—	S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 6.6A⑥
Q <sub>g</sub>	Total Gate Charge	—	—	52	nC	I <sub>D</sub> = 11A
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	13		V <sub>DS</sub> = 400V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	—	18		V <sub>GS</sub> = 10V, See Fig. 6 and 13 ④⑥
t <sub>d(on)</sub>	Turn-On Delay Time	—	14	—	ns	V <sub>DD</sub> = 250V
t <sub>r</sub>	Rise Time	—	35	—		I <sub>D</sub> = 11A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	32	—		R <sub>G</sub> = 9.1Ω
t <sub>f</sub>	Fall Time	—	28	—		R <sub>D</sub> = 22Ω, See Fig. 10 ④⑥
C <sub>iss</sub>	Input Capacitance	—	1423	—	pF	V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance	—	208	—		V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	8.1	—		f = 1.0MHz, See Fig. 5⑥
C <sub>oss</sub>	Output Capacitance⑥	—	2000	—		V <sub>GS</sub> = 0V, V <sub>DS</sub> = 1.0V, f = 1.0MHz
C <sub>oss</sub>	Output Capacitance⑥	—	55	—		V <sub>GS</sub> = 0V, V <sub>DS</sub> = 400V, f = 1.0MHz
C <sub>oss eff.</sub>	Effective Output Capacitance	—	97	—		V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 400V ⑤⑥

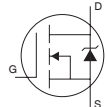
## Avalanche Characteristics

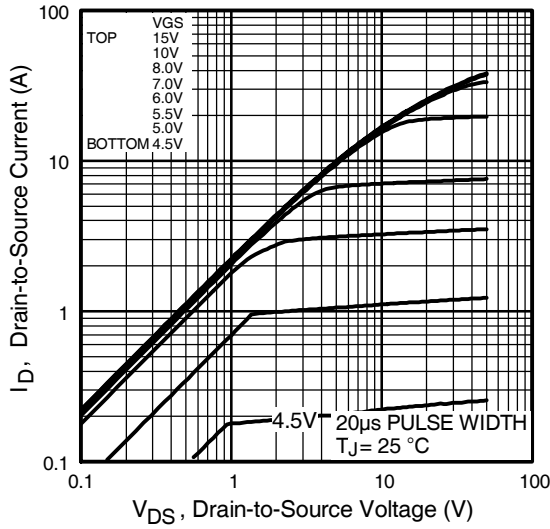
	Parameter	Typ.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy②⑥	—	275	mJ
I <sub>AR</sub>	Avalanche Current①⑥	—	11	A
E <sub>AR</sub>	Repetitive Avalanche Energy①	—	6.0	mJ

## Thermal Resistance

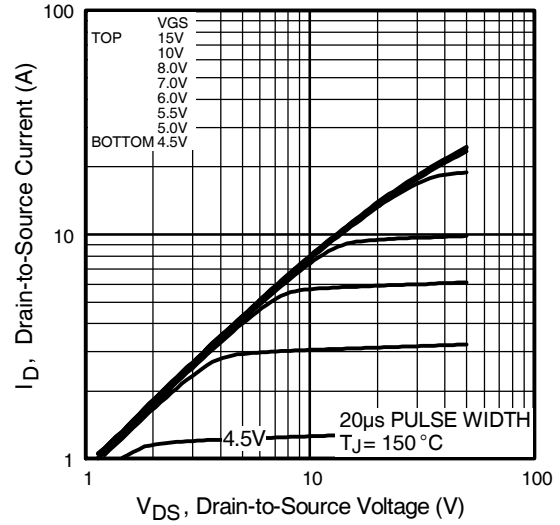
	Parameter	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case	—	2.1	°C/W
R <sub>θJA</sub>	Junction-to-Ambient	—	65	

## Diode Characteristics

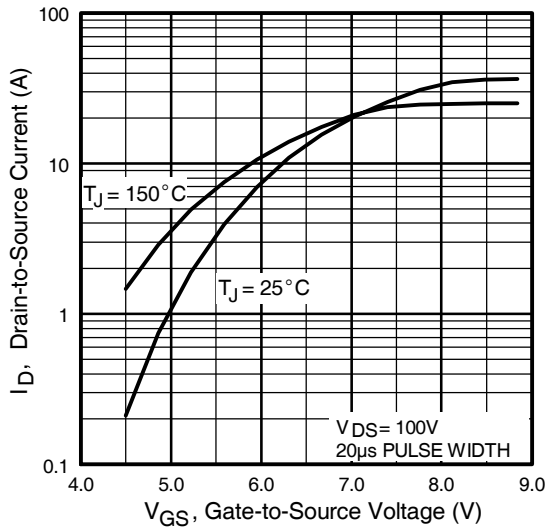
	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	6.6	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①⑥	—	—	44		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.5	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 11A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	510	770	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 11A
Q <sub>rr</sub>	Reverse Recovery Charge	—	3.4	5.1	μC	di/dt = 100A/μs ④⑥
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				



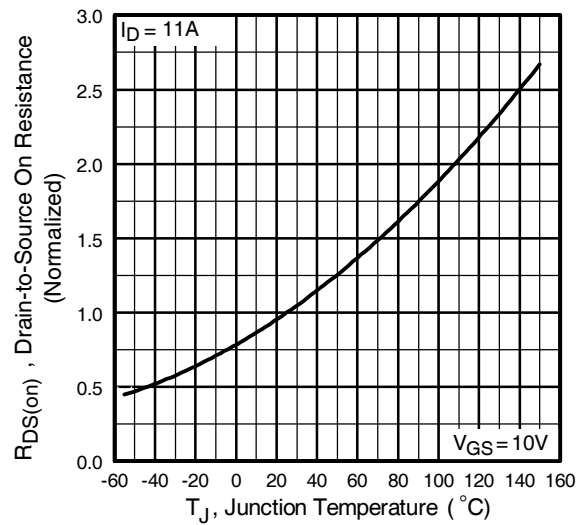
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics

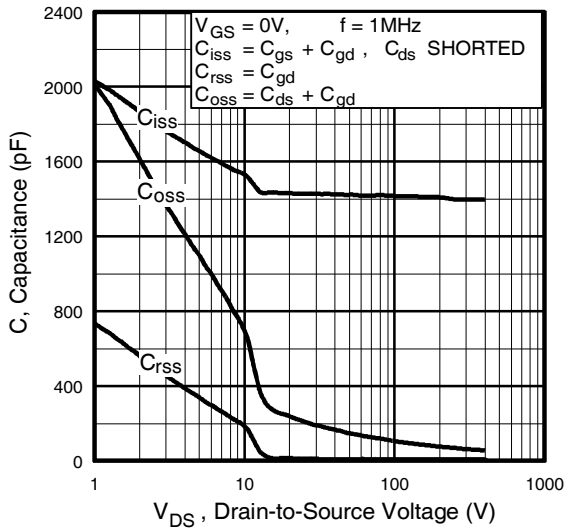


**Fig 3.** Typical Transfer Characteristics

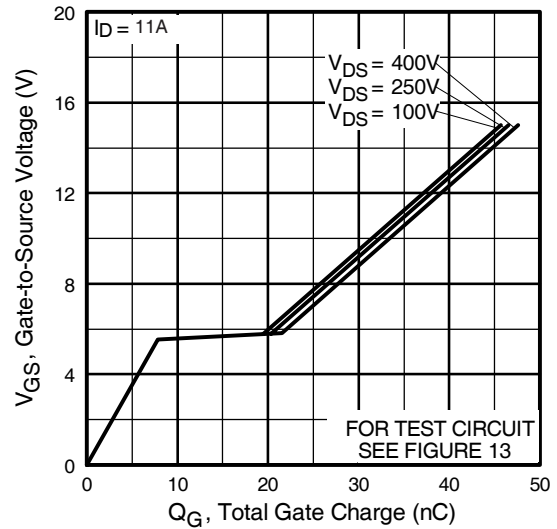


**Fig 4.** Normalized On-Resistance Vs. Temperature

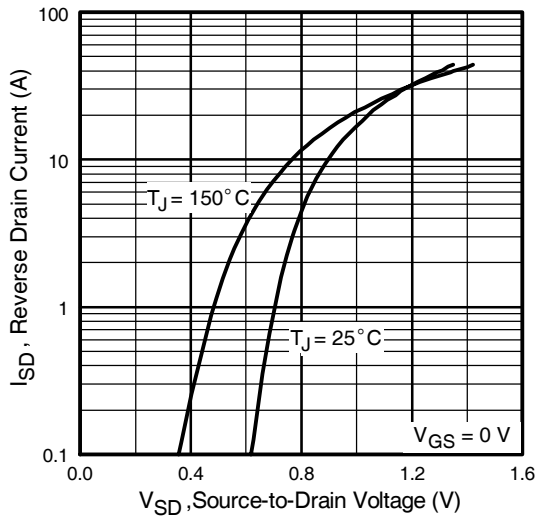
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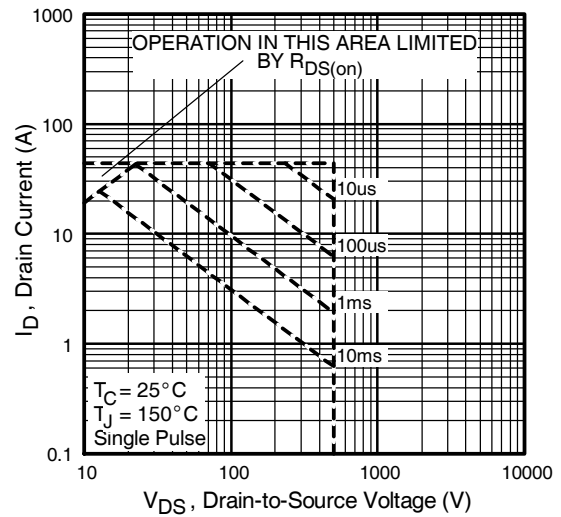
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



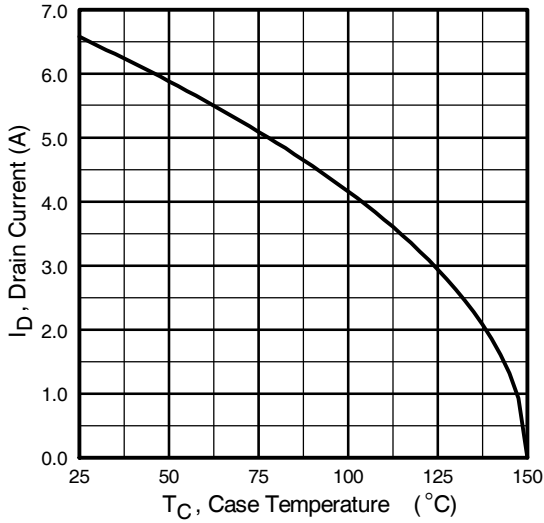
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



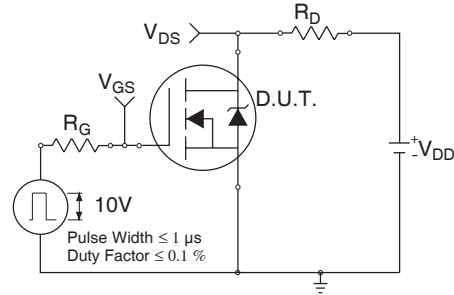
**Fig 7.** Typical Source-Drain Diode Forward Voltage



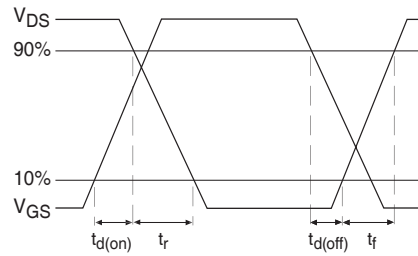
**Fig 8.** Maximum Safe Operating Area



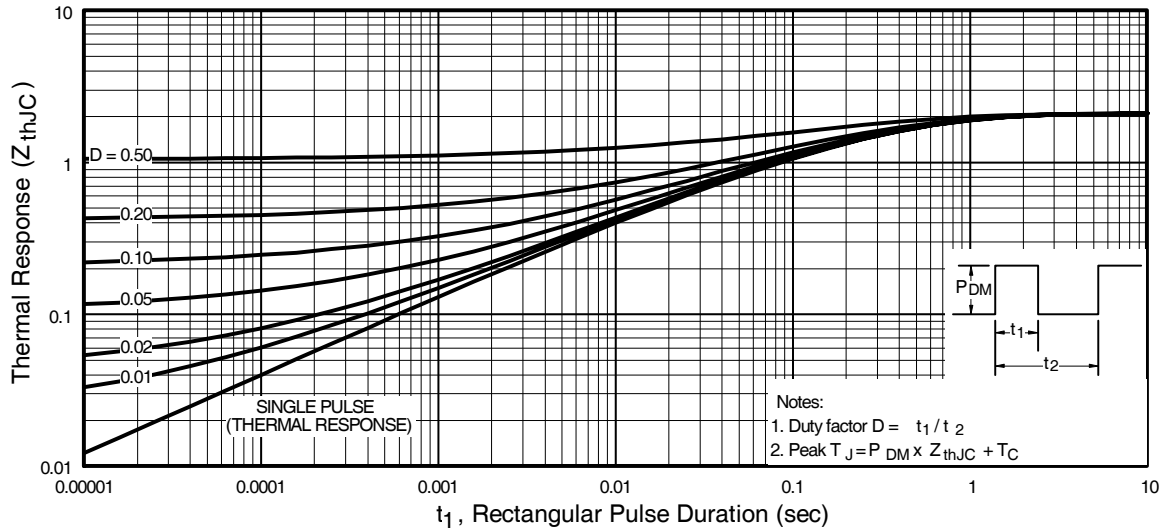
**Fig 9.** Maximum Drain Current Vs. Case Temperature



**Fig 10a.** Switching Time Test Circuit



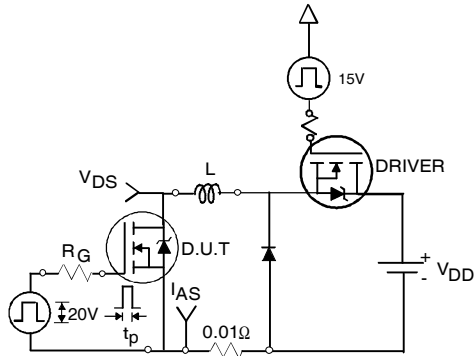
**Fig 10b.** Switching Time Waveforms



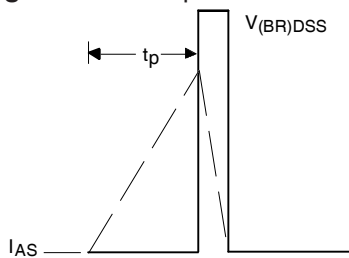
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

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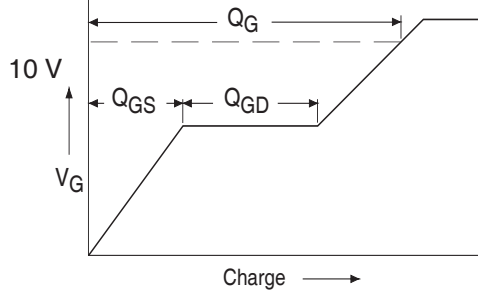
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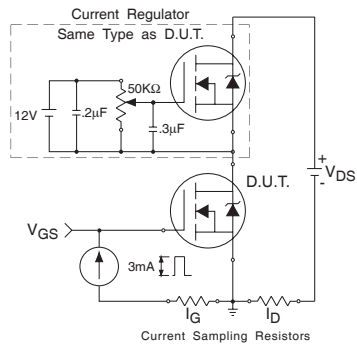
**Fig 12a.** Unclamped Inductive Test Circuit



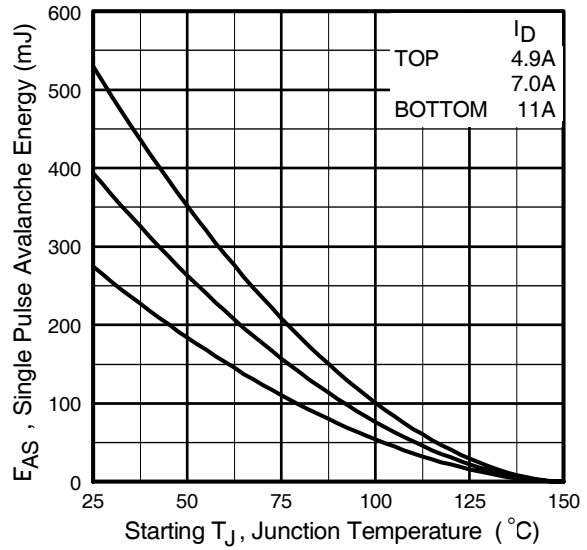
**Fig 12b.** Unclamped Inductive Waveforms



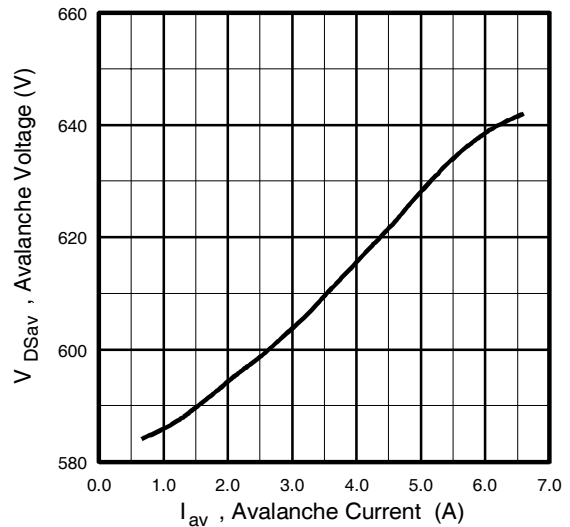
**Fig 13a.** Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit

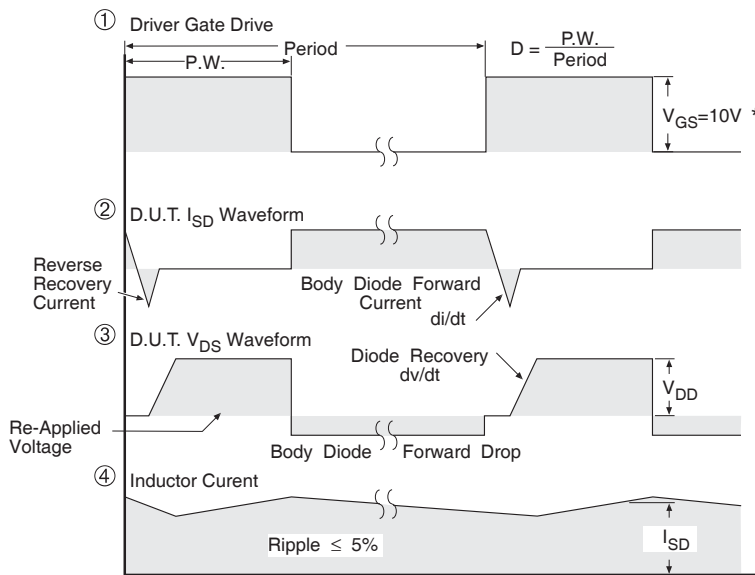
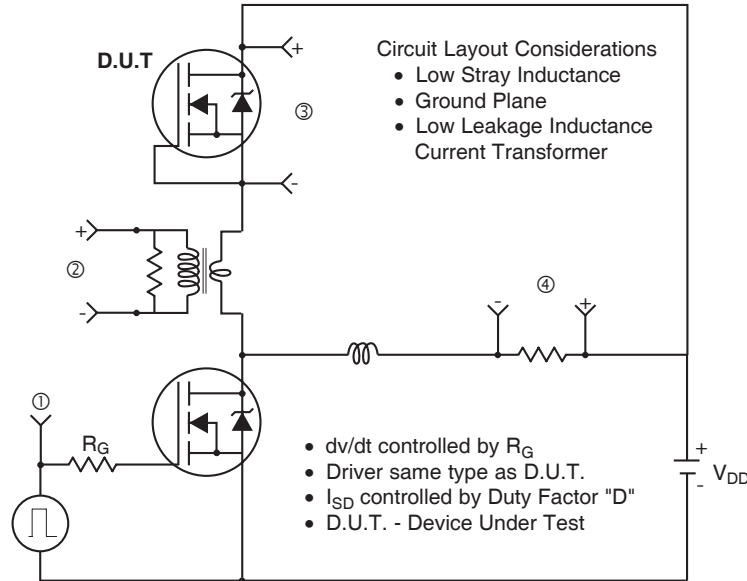


**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 12d.** Typical Drain-to-Source Voltage Vs. Avalanche Current

## Peak Diode Recovery dv/dt Test Circuit



\*  $V_{GS} = 5V$  for Logic Level Devices

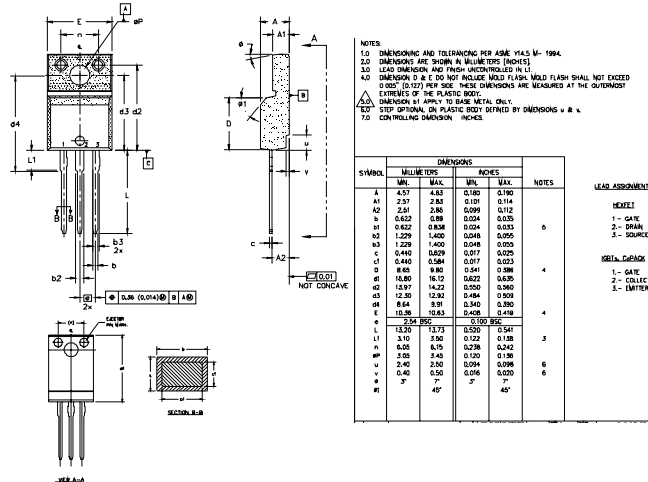
**Fig 14.** For N-Channel HEXFETS

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## TO-220 Full-Pak Package Outline

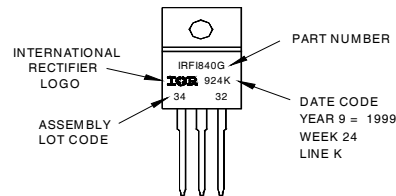
Dimensions are shown in millimeters (inches)



## TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFIB40G  
WITH ASSEMBLY  
LOT CODE 3432  
ASSEMBLED ON WW 24 1999  
IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line position indicates "Lead-Free"



### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 4.5\text{mH}$   
 $R_G = 25\Omega$ ,  $I_{AS} = 11\text{A}$ . (See Figure 12)
- ③  $I_{SD} \leq 11\text{A}$ ,  $di/dt \leq 140\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  
 $T_J \leq 150^\circ\text{C}$
- ④ Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{OSS}$  eff. is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$
- ⑥ Uses IRFB11N50A data and test conditions
- ⑦  $t = 60\text{s}, f = 60\text{Hz}$

Data and specifications subject to change without notice.

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IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105  
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